



INFORMATION DISCLOSURE CITATION

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ATTY DOCKET NO.

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SERIAL NO.

US Div'l of 10/465,075

Naor WAINER et al.

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To be assigned 2873

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
OG	1	4,210,805	1 Jul '80	KOBAYASHI, T. et al.			
OG	2	4,755,676	5 Jul '88	GAALEMA, S. et al.			
OG	3	5,677,539	14 Oct '97	APOTOVSKY, B. et al.			
OG	4	5,777,338	7 Jul '98	HE, Z.			
OG	5	5,821,539	13 Oct '98	MATZ, R. et al.			
OG	6	6,034,373	7 Mar '00	SHAHAR, A. et al.			
OG	7	6,169,287	2 Jan '01	WARBURTON, W. K.			
OG	8	6,583,420	June 2003	NELSON, et al.			
OG	9	6,333,504	Dece 2001	LINGREN, et al.			
OG	10	2002/0079456	June 2002	LINGREN, et al.			
OG	11	5,500,534	March 1996	ROBINSON, et al.			

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
OG	12	CH 471 392	15 Apr '69	SWITZERLAND				
OG	13	DE 196 16 545	30 Oct '97	GERMANY				
OG	14	EP 0 291 351	17 Nov '88	EUROPE				
OG	15	EP 0 527 373	17 Feb '93	EUROPE				
OG	16	FR 2 705 791	2 Dec '94	FRANCE				

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

OG	17	HE, Z. et al.; "Coplanar Grid Patterns and Their Effect on Energy Resolution of CdZnTe Detectors;" IEEE Nuclear Science Symposium and Medical Imaging Conference; Albuquerque, Mexico; 9-15 November 1997
OG	18	NAOAKI, I.; JP 02-163691 A; 22 June 1990 & Patent Abstracts of Japan; Vol. 014; No. 422 (P-1104); 12 September 1990

EXAMINER

Phil Gulee

DATE CONSIDERED

03/15/05

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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DOCUMENT

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OG	21	NAOAKI, I.; JP 05-333157.A; 17 December 1993 & Patent Abstracts of Japan; Vol. 018; No. 162 (P-1712); 17 March 1994
OG	22	NAOKI, S.; JP 59-132382; 30 July 1984 & Patent Abstracts of Japan; Vol. 008; No. 265 (P-318); 5 December 1984

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